

## P-Ch 30V Fast Switching MOSFETs

### Features

- ★ Super Low Gate Charge
- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

### Description

The KWE3031 is the high cell density trenched P-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The KWE3031 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

### Product Summary

BVDSS	RDS <sub>ON</sub>	ID
-30V	7.2mΩ	-50A

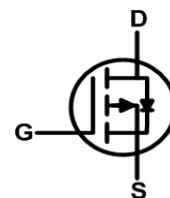
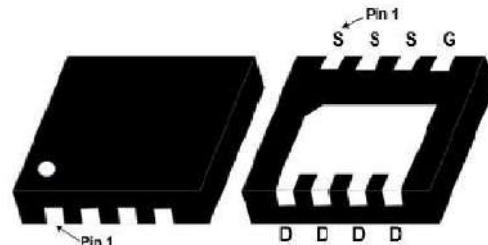
### Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	-30	V
V <sub>GS</sub>	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-50	A
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-31	A
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	-120	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	80	mJ
I <sub>AS</sub>	Avalanche Current	-40	A
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>	41	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C

### Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R <sub>θJA</sub>	Thermal Resistance Junction-ambient <sup>1</sup> (t≤10S)	---	35	°C/W
	Thermal Resistance Junction-ambient <sup>1</sup> (Steady State)	---	55	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-case <sup>1</sup>	---	3	°C/W

**DFN3.3x3.3 Pin Configuration**



### Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_D=-250\mu\text{A}$	-30	---	---	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=-10\text{V}$ , $I_D=-20\text{A}$	---	---	7.2	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}$ , $I_D=-15\text{A}$	---	---	12	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{GS}}=V_{\text{DS}}$ , $I_D=-250\mu\text{A}$	-1.2	---	-2.5	V
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=-24\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $T_J=25^{\circ}\text{C}$	---	---	-1	$\text{uA}$
		$V_{\text{DS}}=-24\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $T_J=55^{\circ}\text{C}$	---	---	-5	
$I_{\text{GSS}}$	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$ , $V_{\text{DS}}=0\text{V}$	---	---	$\pm 100$	nA
$R_g$	Gate Resistance	$V_{\text{DS}}=0\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	---	1.2	---	$\Omega$
$Q_g$	Total Gate Charge (-10V)	$V_{\text{DS}}=-15\text{V}$ , $V_{\text{GS}}=-10\text{V}$ , $I_D=-18\text{A}$	---	60	---	$\text{nC}$
$Q_{\text{gs}}$	Gate-Source Charge		---	9	---	
$Q_{\text{gd}}$	Gate-Drain Charge		---	15	---	
$T_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}}=-15\text{V}$ , $V_{\text{GS}}=-10\text{V}$ , $R_g=3.3\Omega$ , $I_D=20\text{A}$	---	17	---	$\text{ns}$
$T_r$	Rise Time		---	40	---	
$T_{\text{d(off)}}$	Turn-Off Delay Time		---	55	---	
$T_f$	Fall Time		---	13	---	
$C_{\text{iss}}$	Input Capacitance	$V_{\text{DS}}=-25\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	---	3450	---	$\text{pF}$
$C_{\text{oss}}$	Output Capacitance		---	255	---	
$C_{\text{rss}}$	Reverse Transfer Capacitance		---	140	---	

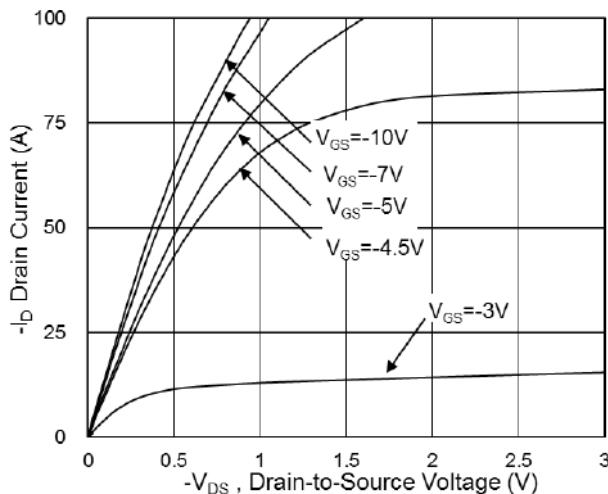
### Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$I_s$	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0\text{V}$ , Force Current	---	---	-50	A
$V_{\text{SD}}$	Diode Forward Voltage <sup>2</sup>	$V_{\text{GS}}=0\text{V}$ , $I_s=-1\text{A}$ , $T_J=25^{\circ}\text{C}$	---	---	-1.2	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_F=-20\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$ , $T_J=25^{\circ}\text{C}$	---	22	---	$\text{nS}$
			---	72	---	$\text{nC}$

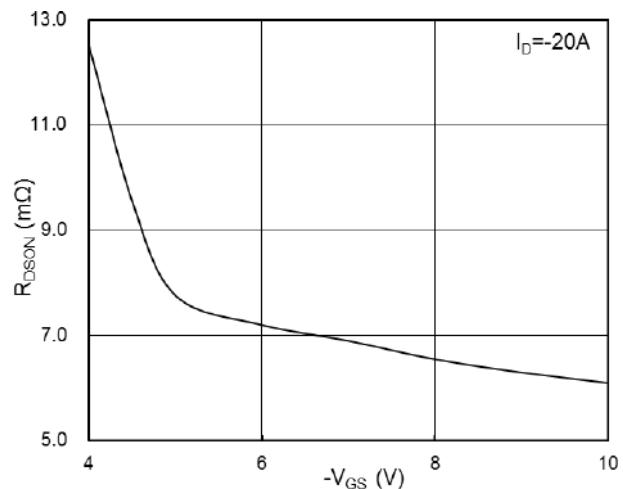
Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
2. The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$
3. The EAS data shows Max. rating . The test condition is  $V_{\text{DD}}=-50\text{V}$ ,  $V_{\text{GS}}=-10\text{V}$ ,  $L=0.1\text{mH}$ ,  $I_{\text{AS}}=-40\text{A}$
4. The power dissipation is limited by  $150^{\circ}\text{C}$  junction temperature
5. The data is theoretically the same as  $I_D$  and  $I_{\text{DM}}$  , in real applications , should be limited by total power dissipation.

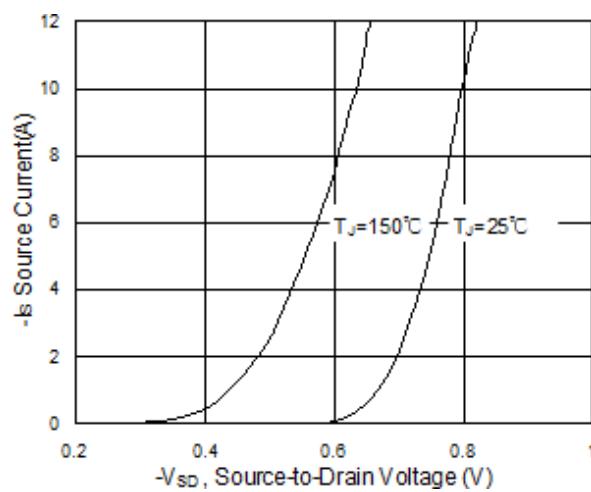
### Typical Characteristics



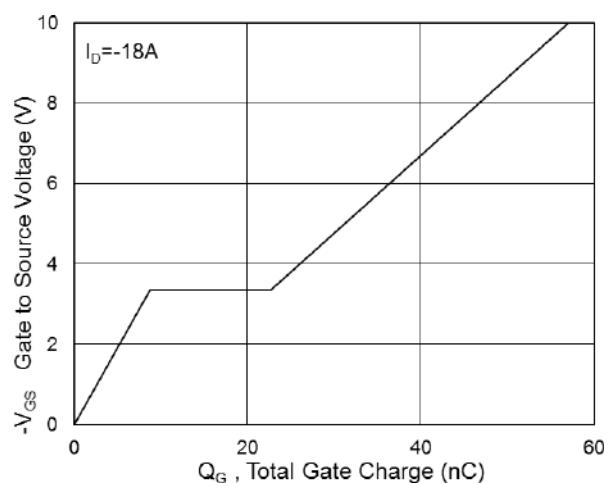
**Fig.1 Typical Output Characteristics**



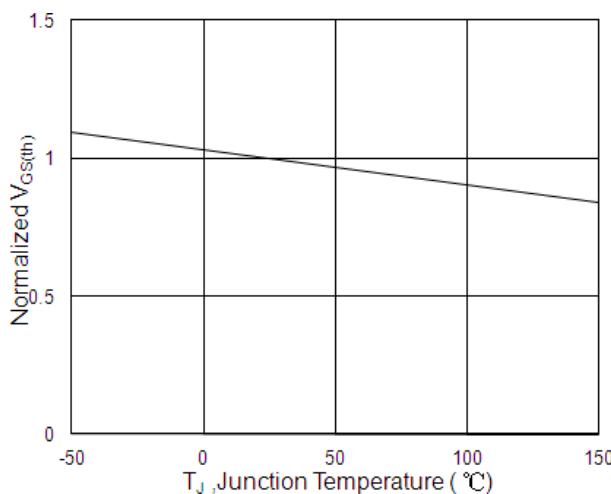
**Fig.2 On-Resistance v.s Gate-Source**



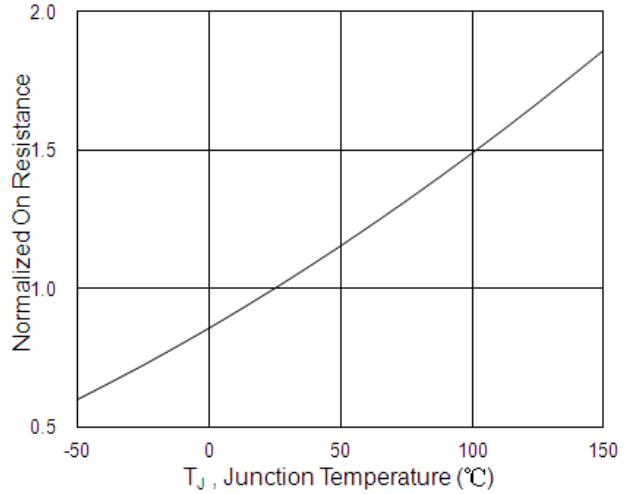
**Fig.3 Forward Characteristics of Reverse**



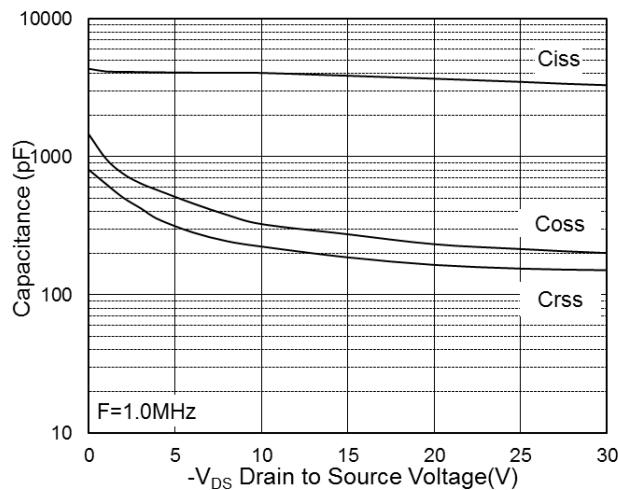
**Fig.4 Gate-Charge Characteristics**



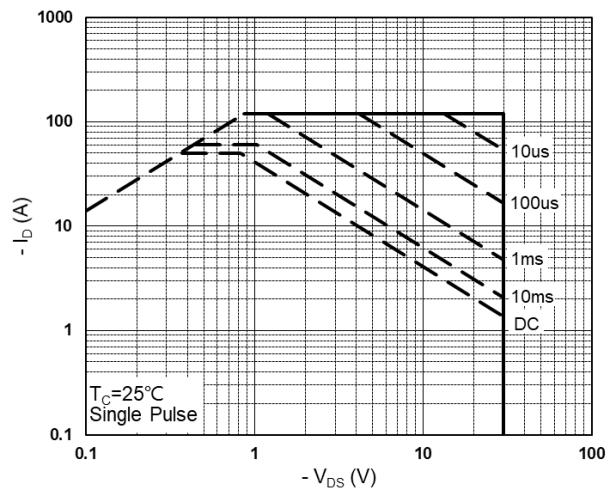
**Fig.5 Normalized  $-V_{GS(th)}$  vs.  $T_J$**



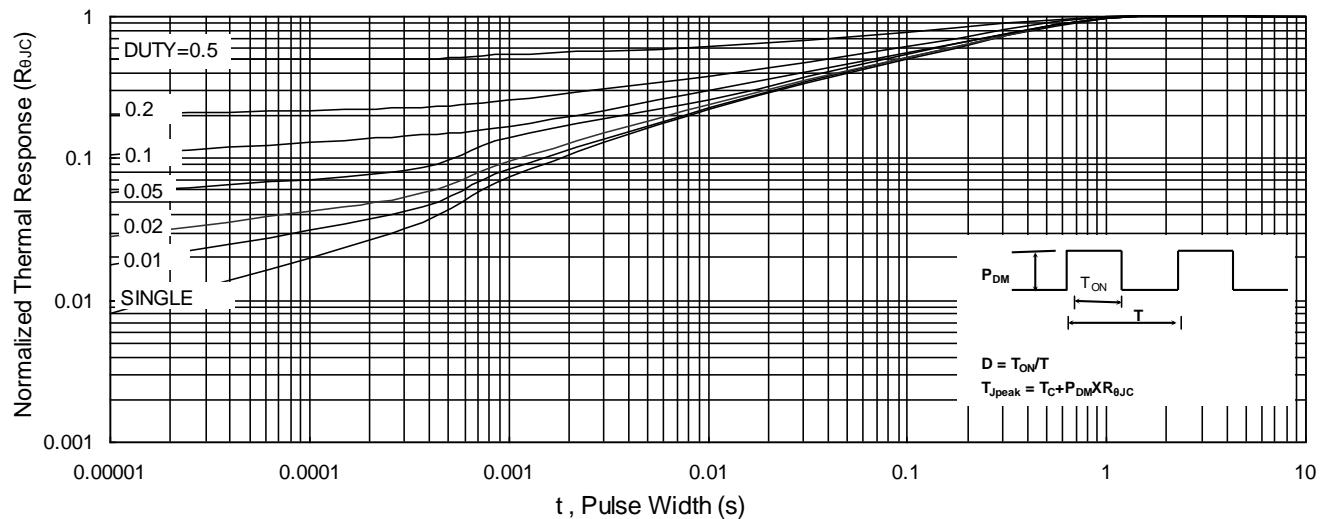
**Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$**



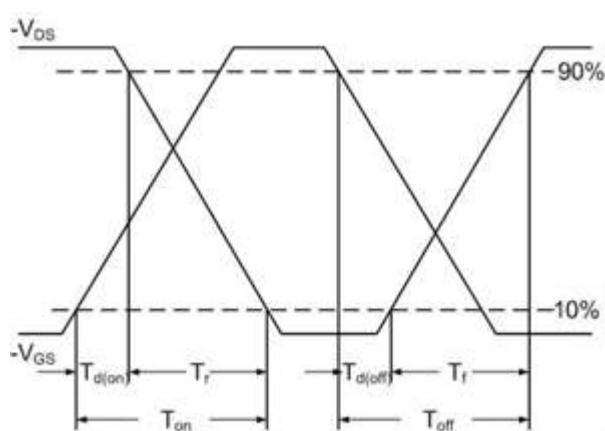
**Fig.7 Capacitance**



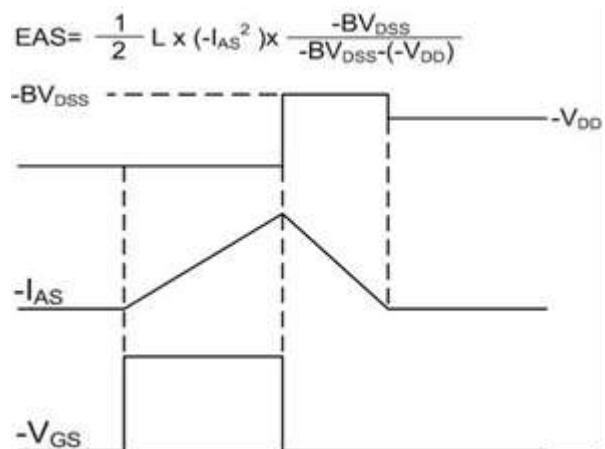
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**

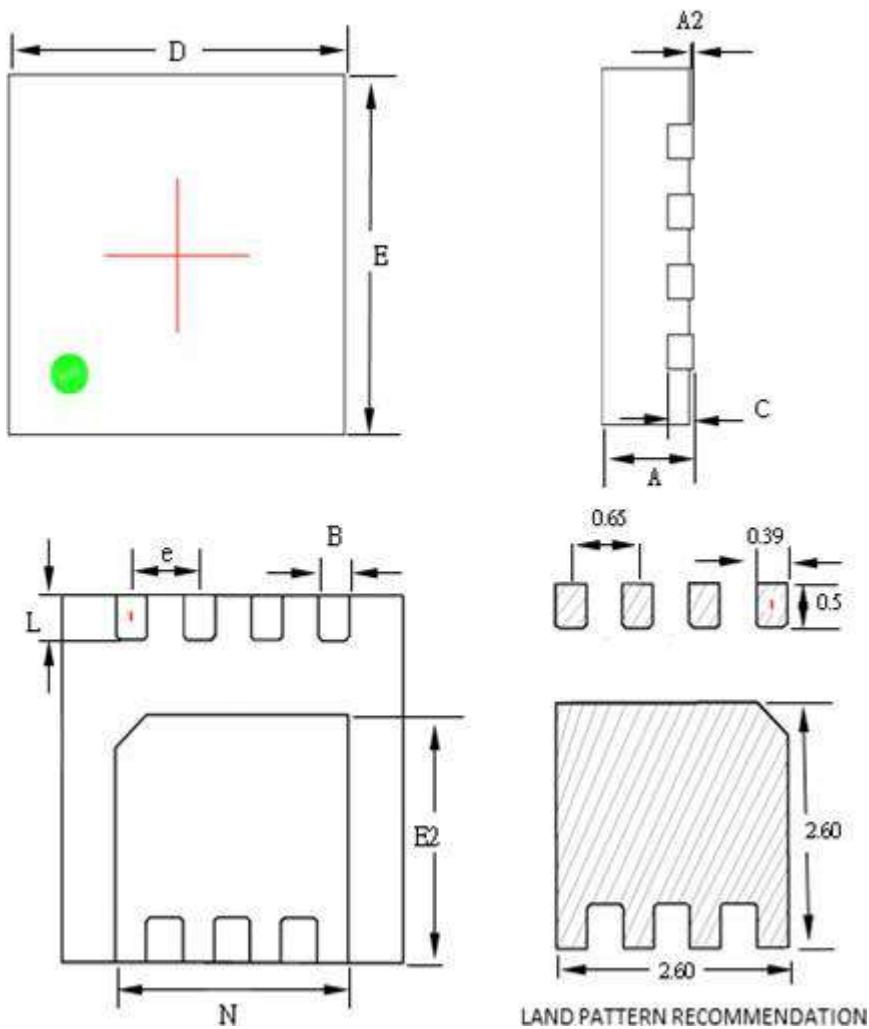


**Fig.10 Switching Time Waveform**



**Fig.11 Unclamped Inductive Switching Waveform**

**DFN3.3x3.3 8L Outline**



<b>SYMBOLS</b>	<b>MILLIMETERS</b>			<b>INCHES</b>		
	<b>MIN</b>	<b>NOM</b>	<b>MAX</b>	<b>MIN</b>	<b>NOM</b>	<b>MAX</b>
<b>A</b>	0.70	0.75	0.80	0.028	0.030	0.031
<b>A2</b>	0.00	--	0.05	0.000	--	0.002
<b>B</b>	0.24	0.30	0.35	0.009	0.012	0.014
<b>C</b>	0.10	0.15	0.25	0.004	0.006	0.010
<b>D</b>	3.15	3.30	3.40	0.124	0.130	0.134
<b>E</b>	3.15	3.30	3.40	0.124	0.130	0.134
<b>E2</b>	2.15	2.25	2.35	0.085	0.089	0.093
<b>L</b>	0.35	0.40	0.45	0.014	0.016	0.018
<b>N</b>	2.10	2.25	2.35	0.083	0.089	0.093
<b>e</b>	--	0.65	--	--	0.026	--